Memory FRAM

256K (256 K × 8) Bit SPI

MB85RS2MTY(AEC-Q100 Compliant)

■ DESCRIPTION

MB85RS2MTY is a FRAM (Ferroelectric Random Access Memory) chip in a configuration of 262,144 words \times 8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells. This product is specifically targeted for high-temperature environment such as automotive applications.

MB85RS2MTY adopts the Serial Peripheral Interface (SPI).

The MB85RS2MTY is able to retain data without using a back-up battery, as is needed for SRAM. The memory cells used in the MB85RS2MTY can be used for 10¹³ read/write operations, which is a significant improvement over the number of read and write operations supported by Flash memory and E²PROM. As MB85RS2MTY does not need any waiting time in writing process, the write cycle time of MB85RS2MTY is much shorter than that of Flash memories or E²PROM.

■ FEATURES

Bit configuration : 262,144 words × 8 bits
 Serial Sector Region : 256 words × 8 bits

In this region, data storage after (by) three times reflow based on

JEDEC MSL-3 standard condition is guaranteed.

Unique IDSerial Number

• Serial Peripheral Interface : SPI (Serial Peripheral Interfaces

Correspondent to SPI mode 0 (0, 0) and mode 3 (1, 1)

Operating frequency
 High endurance
 Data retention
 : 50 MHz (Max)
 : 10¹³ times / byte
 : 10 years (+85 °C)

2 .75years (+105 °C)

0.85 years (+125 °C) or more

Under evaluation for more than 2.5years(+125 °C)

• Operating power supply voltage : 1.8 V to 3.6 V

Low power consumption : Operating power supply current 4 mA (Max@50 MHz)

Standby current 220 µA (Max)

Deep Power Down current 30 μA (Max)

Operation ambient temperature range : – 40 °C to +125 °C

• Package : 8-pin plastic SOP 150mil (FPT-8P)

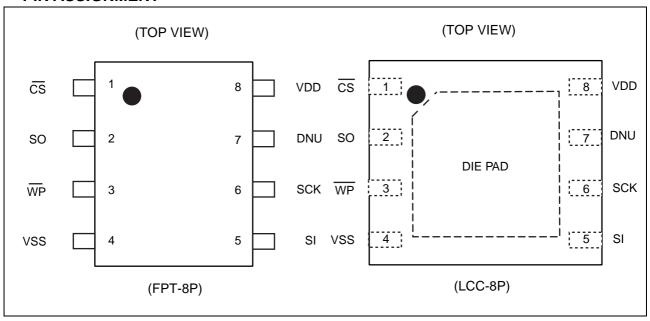
8-pin plastic DFN 5mm × 6mm (LCC-8P)

AEC-Q100 Grade 1 compliant

RoHS compliant



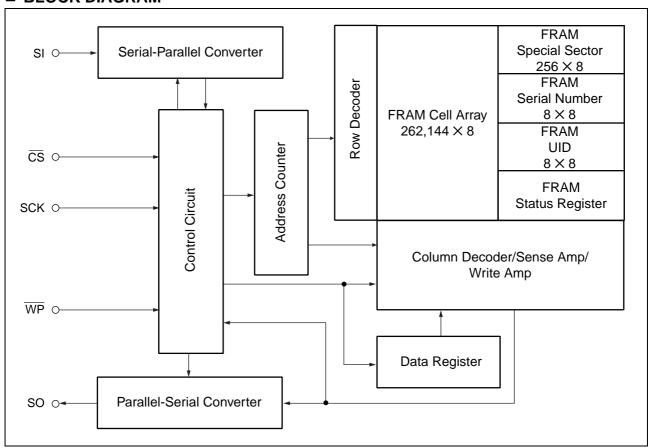
■ PIN ASSIGNMENT



■ PIN FUNCTIONAL DESCRIPTIONS

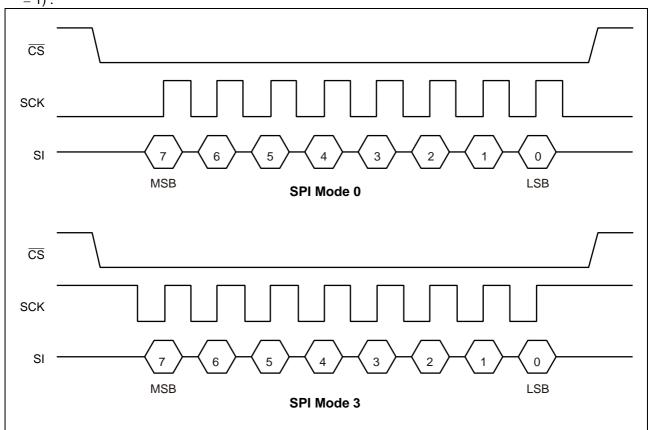
Pin No.	Pin Name	Functional description
1	CS	Chip Select pin This is an input pin to make chips select. When \overline{CS} is "H" level, device is in deselect (standby) status and SO becomes High-Z. Inputs from other pins are ignored for this time. When \overline{CS} is "L" level, device is in select (active) status. \overline{CS} has to be "L" level before inputting op-code.
3	WP	Write Protect pin This is a pin to control writing to a status register. The writing of status register (see "■ STATUS REGISTER") is protected in related with WP and WPEN. See "■WRITING PROTECT" for detail.
7	DNU	DNU pin This pin is not used. It is allowed to be floating (no connection) or to be connected to VDD or VSS.
6	SCK	Serial Clock pin This is a clock input pin to input/output serial data. SI is loaded synchronously to a rising edge, SO is output synchronously to a falling edge.
5	SI	Serial Data Input pin This is an input pin of serial data. This inputs op-code, address, and writing data.
2	SO	Serial Data Output pin This is an output pin of serial data. Reading data of FRAM memory cell array and status register data are output. This is High-Z during standby.
8	VDD	Supply Voltage pin
4	VSS	Ground pin
DIE PAD	_	It is allowed for the DIE PAD on the bottom of the DFN8 package to be floating (no connection to anything) or to be connected to VSS.

■ BLOCK DIAGRAM



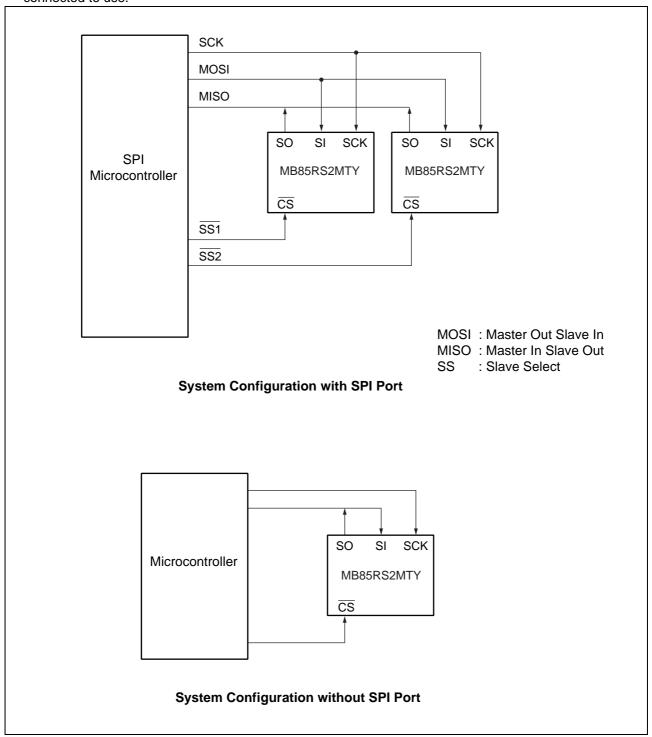
■ SPI MODE

MB85RS2MTY corresponds to the SPI mode 0 (CPOL = 0, CPHA = 0), and SPI mode 3 (CPOL = 1, CPHA = 1).



■ SERIAL PERIPHERAL INTERFACE (SPI)

MB85RS2MTY works as a slave of SPI. More than 2 devices can be connected by using microcontroller equipped with SPI port. By using a microcontroller not equipped with SPI port, SI and SO can be bus connected to use.



■ STATUS REGISTER

Bit No.	Bit Name	Function
7	WPEN	Status Register Write Protect This is a bit composed of nonvolatile memories (FRAM). WPEN protects writing to a status register (refer to "■ WRITING PROTECT") relating with WP input. Writing with the WRSR command and reading with the RDSR command are possible.
6 to 4	_	Not Used Bits These are bits composed of nonvolatile memories, writing with the WRSR command is possible. These bits are not used but they are read with the RDSR command.
3	BP1	Block Protect This is a bit composed of nonvolatile memory. This defines size of write
2	BP0	protect block for the WRITE command (refer to "■ BLOCK PROTECT"). Writing with the WRSR command and reading with the RDSR command are possible.
1	WEL	Write Enable Latch This indicates FRAM Array and status register are writable. The WREN command is for setting, and the WRDI command is for resetting. With the RDSR command, reading is possible but writing is not possible with the WRSR command. WEL is reset after the following operations. After power ON. After WRDI command recognition. After return from DPD mode. Achieving continuous writing mode, WEL is not reset after following operations making it possible to execute writing commands continuously. After WRSR command recognition. After WRSN command recognition. After SSWR command recognition.
0	0	This is a bit fixed to "0".

■ OP-CODE

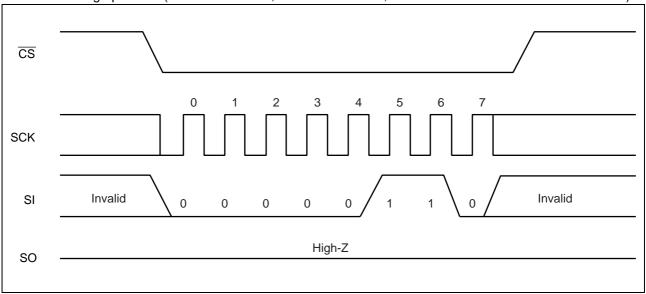
MB85RS2MTY accepts 15 kinds of command specified in op-code. Op-code is <u>a code</u> composed of 8 bits shown in the table below. Do not input invalid codes other than those codes. If $\overline{\text{CS}}$ is risen while inputting op-code, the command are not performed.

Name	Description	Op-code
WREN	Set Write Enable Latch	0000 0110в
WRDI	Reset Write Enable Latch	0000 0100в
RDSR	Read Status Register	0000 0101в
WRSR	Write Status Register	0000 0001в
READ	Read Memory Code	0000 0011в
WRITE	Write Memory Code	0000 0010в
FSTRD	Fast Read Memory Code	0000 1011в
DPD	Deep Power Down Mode	1011 1010в
RDID	Read Device ID	1001 1111в
RUID	Read Unique ID	0100 1100в
WRSN	Write Serial Number	1100 0010в
RDSN	Read Serial Number	1100 0011в
SSWR	Write Special Sector	0100 0010в
SSRD	Read Special Sector	0100 1011в
FSSRD	Fast Read Special Sector	0100 1001в
		1011 1001в
		1100 0001в
RFU	Reserved	1100 0110в
		1100 1110в
		1100 1111в

■ COMMAND

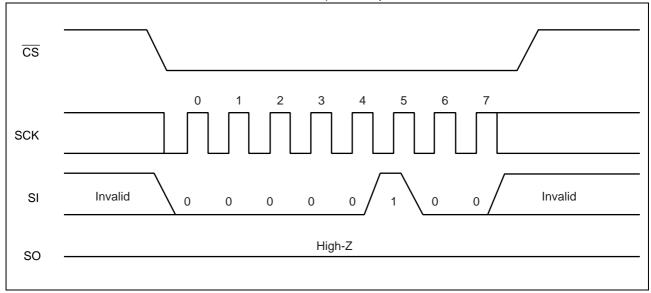
• WREN

The WREN command sets WEL (Write Enable Latch) bit to 1. WEL has to be set with the WREN command before writing operation (WRSR command, WRITE command, WRSN command and SSWR command).



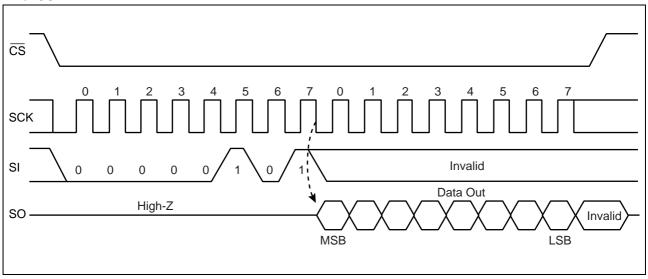
• WRDI

The WRDI command resets WEL (Write Enable Latch) bit to 0. Writing operation (WRSR command, WRITE command, WRSN command and SSWR command) are not performed when WEL is reset.



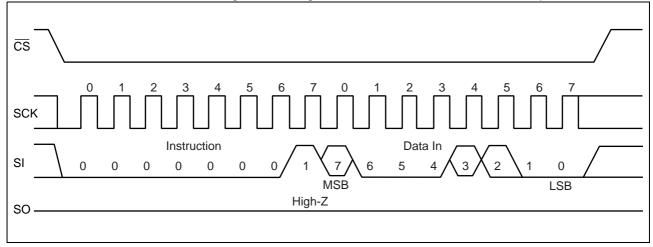
• RDSR

The RDSR command reads status register data. After op-code of RDSR is input to SI, 8-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. In the RDSR command, repeated reading of status register is enabled by sending SCK continuously before rising of CS.



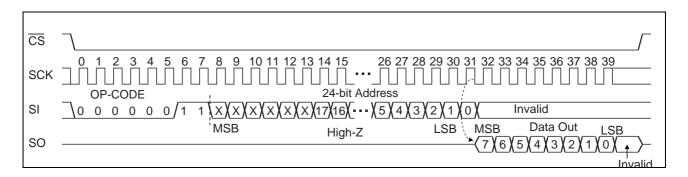
• WRSR

The WRSR command writes data to the nonvolatile memory bit of status register. After performing WRSR op-code to a SI pin, 8 bits writing data is input. WEL (Write Enable Latch) is not able to be written with WRSR command. A SI value correspondent to bit 1 is ignored. Bit <u>0 of</u> the status register is fixed to "0" and cannot be written. The SI value corresponding to <u>bit 0</u> is ignored. WP signal level shall be fixed before performing WRSR command, and do not change the <u>WP</u> signal level until the end of command sequence.



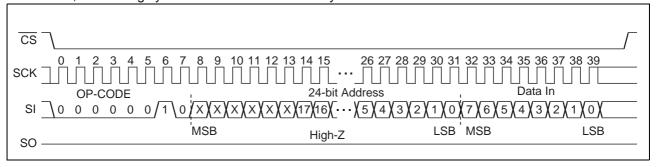
• READ

The READ command reads FRAM memory cell array data. Arbitrary 16 bits address and op-code of READ are input to SI. The most significant address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When \overline{CS} is risen, the READ command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before \overline{CS} rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



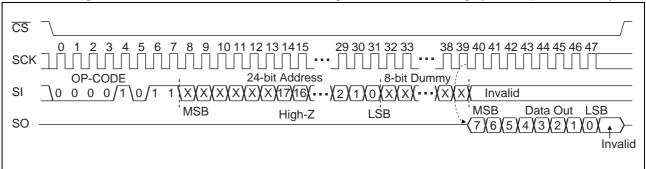
• WRITE

The WRITE command writes data to FRAM memory cell array. WRITE op-code, arbitrary 16 bits of address and 8 bits of writing data are input to SI. The most significant address bit is invalid. When 8 bits of writing data is input, data is written to FRAM memory cell array. Risen CS will terminate the WRITE command, but if you continue sending the writing data for 8 bits each before CS rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, it rolls over to the starting address, and writing cycle can be continued infinitely.



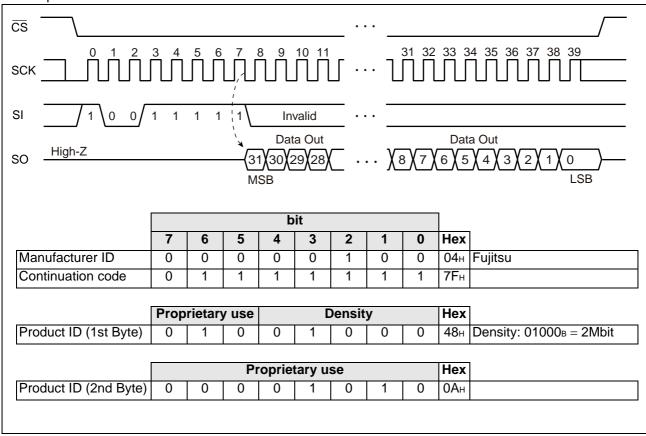
• FSTRD

The FSTRD command reads FRAM memory cell array data. Arbitrary 24 bits address and op-code of FSTRD are input to SI followed by 8 bits dummy. The 6-bit upper address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When CS is risen, the FSTRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before CS rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



• RDID

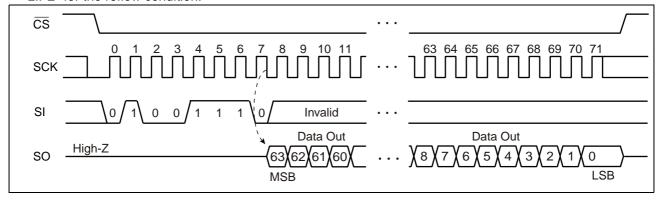
The RDID command reads fixed Device ID. After performing RDID op-code to SI, 32-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. The output is in order of Manufacturer ID (8bit)/Continuation code (8bit)/Product ID (1st Byte)/Product ID (2nd Byte). In the RDID command, 32-bit \underline{Device} ID is output by continuously sending SCK clock, and SO holds the output state of the last bit until \overline{CS} is risen.



RUID

The RUID command reads an unique ID which is defined in 64bits for each device. After performing RUID op-code to SI, 64-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK.

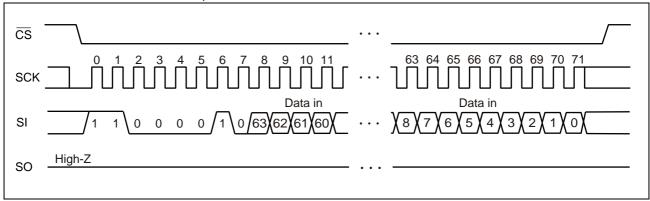
The unique ID is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



•WRSN

The WRSN command writes data to serial number region which is allowed to write only one time. After performing WRSN op-code to SI, 64bits of writing data is input. Once wrote, the serial number region is protected, disabling to overwrite even when issuing WRSN command.

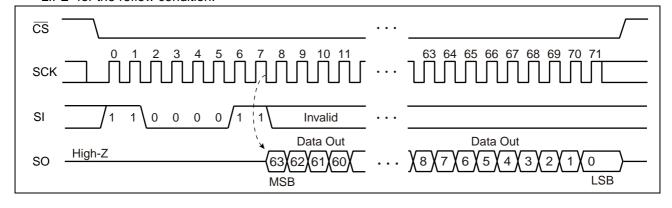
WP signal level shall be fixed before performing WRSN command, and do not change the WP signal level until the end of command sequence.



•RDSN

The RDSN command reads 64 bits of serial number which is written using WRSN command. After performing RDSN op-code to SI, 64-cycle clock to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. When reading serial number from devices which no WRSN command is executed, "0" for all bits are output.

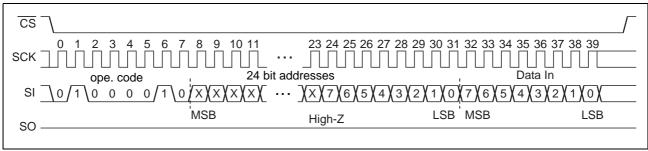
The serial number is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



• SSWR

The SSWR command writes data to special sector (a special region of 256 Byte in FRAM). SSWR op-code, arbitrary 24 bits address and 8-bit writing data are input to SI. The 16-bit upper address is invalid. When input of 8-bit writing data is completed, it starts writing data to special sector. Risen \overline{CS} will terminate the SSWR command, but if you continue the writing data for each before \overline{CS} rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, roll over is not happen, the data hereafter is ignored.

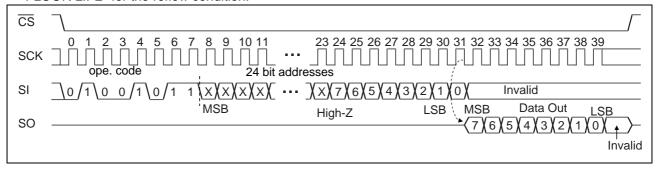
The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



• SSRD

The SSRD command reads data from special sector (a special region of 256 Byte in FRAM). SSWR opcode and arbitrary 24 bits address are input to SI. The 16-bit upper address is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When $\overline{\text{CS}}$ is risen, the SSRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before $\overline{\text{CS}}$ rising. When it reaches the most significant address, roll over is not happen.

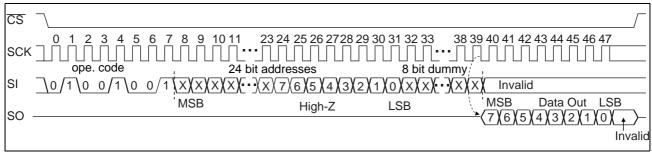
The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



• FSSRD

The SSRD command reads data from special sector (a special region of 256 Byte in FRAM). SSWR opcode and arbitrary 24 bits address are input to SI followed by 8 bits dummy. The 16-bit upper address is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When $\overline{\text{CS}}$ is risen, the SSRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before $\overline{\text{CS}}$ rising. When it reaches the most significant address, roll over is not happen.

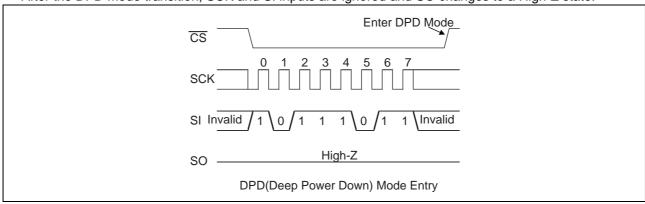
The data in special sector is stable between before and after reflow. Refer "■ REFLOW CONDITIONS AND FLOOR LIFE" for the reflow condition.



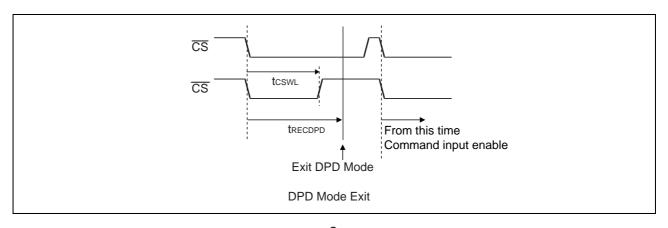
• DPD(Deep Power Down)

The DPD command shifts the LSI to a low power mode called "DPD mode". The transition to the DPD mode is carried out at the rising edge of \overline{CS} after operation code in the DPD command. However, when at least one SCK clock is inputted before the rising edge of \overline{CS} after operation code in the DPD command, this DPD command is canceled.

After the DPD mode transition, SCK and SI inputs are ignored and SO changes to a High-Z state.



Returning to an normal operation from the DPD mode is carried out after trecded (Max 10 µs) time from the falling edge of \overline{CS} (see the figure below). It is possible to return \overline{CS} to H level before trecded time. However, it is prohibited to bring down \overline{CS} to L level again during trecded period.



■ BLOCK PROTECT

Writing protect block for WRITE command is configured by the value of BP0 and BP1 in the status register.

BP1	BP0	Protected Block
0	0	None
0	1	6000н to 7FFFн (upper 1/4)
1	0	4000н to 7FFFн (upper 1/2)
1	1	0000н to 7FFFн (all)

■ WRITING PROTECT

Writing operation of the WRITE command and the WRSR command are protected with the value of WEL, WPEN, WP as shown in the table.

WEL	WPEN	WP	Protected Blocks	Unprotected Blocks	Status Register
0	Х	Х	Protected	Protected	Protected
1	0	Х	Protected	Unprotected	Unprotected
1	1	0	Protected	Unprotected	Protected
1	1	1	Protected	Unprotected	Unprotected

■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ra	Unit	
Farameter	Symbol	Min	Max	Unit
Power supply voltage*	V _{DD}	- 0.5	+ 4.0	V
Input voltage*	Vin	- 0.5	$V_{DD} + 0.5 (\le 4.0)$	V
Output voltage*	Vоит	- 0.5	$V_{DD} + 0.5 (\le 4.0)$	V
Operation ambient temperature	TA	- 40	+ 125	°C
Storage temperature	Tstg	- 55	+ 150	°C

^{*:} These parameters are based on the condition that Vss is 0 V.

WARNING: Semiconductor devices may be permanently damaged by application of stress (including, without limitation, voltage, current or temperature) in excess of absolute maximum ratings.

Do not exceed any of these ratings.

■ RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit		
Farameter	Symbol	Min	Тур	Max	Offic
Power supply voltage*1	V_{DD}	1.8	3.3	3.6	V
Operation ambient temperature*2	TA	- 40		+ 125	°C

^{*1:} These parameters are based on the condition that Vss is 0 V.

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated under these conditions.

Any use of semiconductor devices will be under their recommended operating condition. Operation under any conditions other than these conditions may adversely affect reliability of device and could result in device failure.

No warranty is made with respect to any use, operating conditions or combinations not represented on this data sheet. If you are considering application under any conditions other than listed herein, please contact sales representatives beforehand.

^{*2:} Ambient temperature when only this device is working. Please consider it to be the almost same as the package surface temperature.

■ ELECTRICAL CHARACTERISTICS

1. DC Characteristics

(within recommended operating conditions)

Baramatar	Symbol	Conditio		Value		l lni4	
Parameter	Symbol	Conditio	Condition		Тур	Max	Unit
		$\overline{CS} = V_{DD}$	25 °C			1	
Input lookaga gurrant*1	Heat	C3 = V DD	125 °C			2	^
Input leakage current*1	lu	WP, SCK, CS	25 °C	_		1	μΑ
		$SI = 0 V to V_{DD}$	125 °C			2	
Output lookaga aurrant*2	lli al	SO 0 1/ to 1/	25 °C	_		1	^
Output leakage current*2	ILO	$SO = 0 V to V_{DD}$	125 °C			2	μΑ
Operating power supply current*3	lob	SCK = 50N	_	3.2	4	mA	
Standby current	lsв	$SCK = SI = \overline{Q}$ $\overline{WP} = V_{DI}$		_	11	220	μА
Sleep current	lzz	CS = V _{DD} All inputs V _{SS} or V _{DD}		_	6	30	μА
Input high voltage	VIH	V _{DD} = 1.8 V to 3.6 V		$V_{\text{DD}} \times 0.7$		V _{DD} + 0.3	V
Input low voltage	VıL	V _{DD} = 1.8 V to 3.6 V		- 0.3		$V_{DD} \times 0.3$	V
Output high voltage	Vон	Iон = −2 mA		V _{DD} - 0.5		_	V
Output low voltage	Vol	lol = 2 m/	٩			0.4	V

^{*1 :} Applicable pin : $\overline{\text{CS}}$, $\overline{\text{WP}}$, SCK, SI

^{*2 :} Applicable pin : SO

 $^{^*3}$: Input voltage magnitude: VDD – 0.2 V or VSS

2. AC Characteristics

Daramatar	Cumbal	Va	lue	l lmi4	Condition	
Parameter	Symbol	Min	Max	Unit	V_{DD}	
SCK clock frequency	fcк	_	50	MHz	all commands ex- cept for READ/ SSRD	
		_	40		READ command	
		_	10		SSRD command	
Clock high time	t cH	9		ns		
Clock low time	t cL	9		ns		
Chip select set up time	t csu	11		ns		
Chip select hold time	tсsн	5	_	ns		
Output disable time	top	_	10	ns		
Output data valid time	todv	_	9	ns	*1	
Output hold time	tон	0	_	ns		
Deselect time	t⊳	40	_	ns		
Data in rising time	t R	_	50	ns		
Data falling time	tF	_	50	ns		
Data set up time	t su	5	_	ns		
Data hold time	tн	5	_	ns		
DPD recovery pulse width	tcswL	100	_	_		
DPD recovery time	t RECDPD	_	10	μS		

^{*1:} In SSRD command, 60ns(max.)

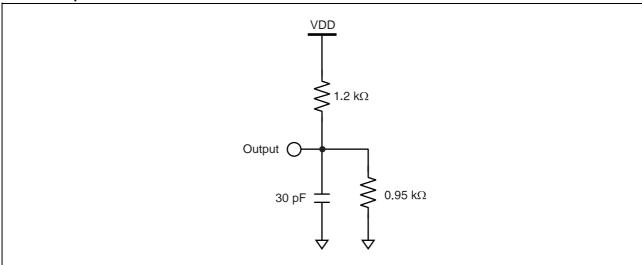
AC Test Condition

Power supply voltage : 1.8 V to 3.6 V Operation Operation ambient temperature : -40 °C to +125 °C Input voltage magnitude : $V_{DD} \times 0.8 \le V_{IH} \le V_{DD}$

 $0 \leq V_{\text{IL}} \leq V_{\text{DD}} \times 0.2$

Input rising time : 5 ns
Input falling time : 5 ns
Input judge level : VDD/2
Output judge level : VDD/2

AC Load Equivalent Circuit



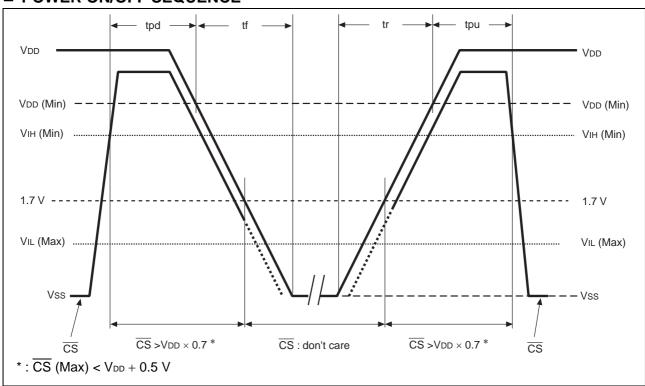
3. Pin Capacitance

Parameter	Symbol	Condition	Va	Unit	
r ai ailletei	Symbol	Condition	Min	Max	Onit
Output capacitance	Со	$V_{DD} = 3.3 \text{ V},$ $V_{IN} = V_{OUT} = 0 \text{ V to } V_{DD},$	_	8	pF
Input capacitance	Cı	f = 1 MHz, T _A = +25 °C	_	6	pF

■ TIMING DIAGRAM

• Serial Data Timing $\overline{\text{CS}}$ ► tcsH tcsu tcH tCL tcH SCK tsu Valid in SI todv top toн |◀ High-Z High-Z SO : H or L

■ POWER ON/OFF SEQUENCE



In case relative short V_{DD} pulse whose peak level is beyond 1.7 is applied, please set V_{DD} falling time, tf, longer than 0.4ms/V. (When V_{DD} rises beyond 1.7V, and falls just after, if this term is very short the device may loose its function.).

Parameter	Cumbal	Value		l lmi4	Condition
Parameter	Symbol	Min	Max	Unit	V_{DD}
CS level hold time at power OFF	tnd	400	_	ns	1.8V to 2.7V
CS level floid time at power OFF	tpd	0		115	2.7V to 3.6V
CS level hold time at power ON	tpu	450		μS	_
Power supply rising time	tr	0.05	_	ms/V	_
Power supply falling time	tf	0.1		ms/V	_

If the device does not operate within the specified conditions of read cycle, write cycle or power on/off sequence, memory data can not be guaranteed.

■ FRAM CHARACTERISTICS

Parameter	Value		Unit	Remarks	
Farameter	Min	Max	Oilit	Kemarks	
Read/Write Endurance*1	10 ¹³	—	Times/byte	Operation Ambient Temperature T _A = + 125 °C	
	0.85 or more*3			Operation Ambient Temperature T _A = + 125 °C	
Data Retention*2	2.75	_	Years	Operation Ambient Temperature T _A = + 105 °C	
	10	_		Operation Ambient Temperature T _A = +85 °C	

^{*1:} Total number of reading and writing defines the minimum value of endurance, as an FRAM memory operates with destructive readout mechanism.

^{*2:} Minimum values define retention time of the first reading/writing data right after shipment, and these values are calculated by qualification results.

^{*3:} Under evaluation for more than 0.85years(+125 °C).

■ NOTE ON USE

We recommend programming of the device after reflow except for special sector region and serial number region. Data written before reflow cannot be guaranteed.

■ ESD AND LATCH-UP

Test	DUT	Value
ESD HBM (Human Body Model) JESD22-A114 compliant		≥ 2000 V
ESD CDM (Charged Device Model) AEC-Q100-011(FI-CDM) compliant	MB85RS2MTYPNF-GS-AWE2 MB85RS2MTYPNF-GS-AWERE2 MB85RS2MTYPN-GS-AWEWE1	≥ 500 V
Latch-Up (I-test) JESD78 compliant		≥ 125mA
Latch-Up (V _{supply} overvoltage test) JESD78 compliant		≥ 5.4V

■ REFLOW CONDITIONS AND FLOOR LIFE

[JEDEC MSL] : Moisture Sensitivity Level 3 (ISP/JEDEC J-STD-020D)

■ Current status on Contained Restricted Substances

This product complies with the regulations of REACH Regulations, EU RoHS Directive and China RoHS.

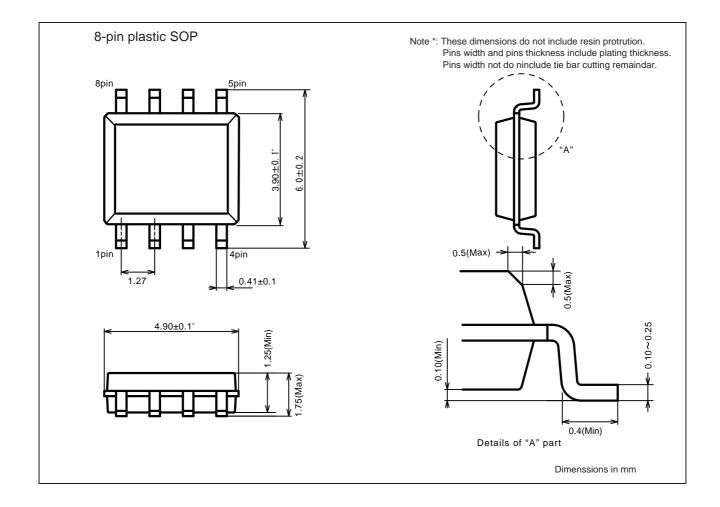
■ ORDERING INFORMATION

Part number	Package	Shipping form	Minimum shipping quantity
MB85RS2MTYPNF-GS-AWE2	8-pin plastic SOP (FPT-8P)	Tube	*
MB85RS2MTYPNF-GS-AWERE2	8-pin plastic SOP (FPT-8P)	Embossed Carrier tape	1500
MB85RS2MTYPN-GS-AWEWE1	8-pin plastic DFN (LCC-8P)	Embossed Carrier tape	1500

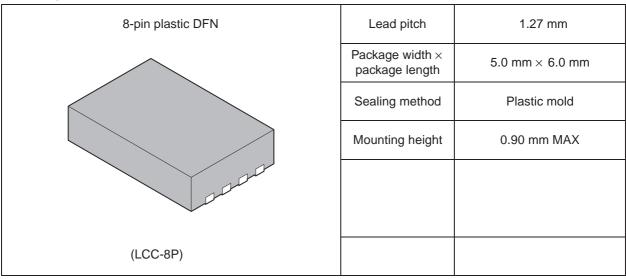
^{* :} Please contact our sales office about minimum shipping quantity.

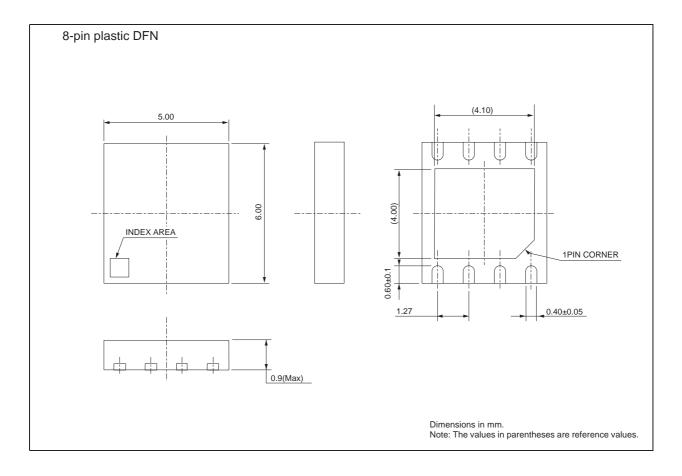
■ PACKAGE DIMENSION

8-pin plastic SOP	Lead pitch	1.27 mm
	Package width × package length	3.9 mm×4.9 mm
	Lead shape	Gullwing
	Sealing method	Plastic mold
	Mounting heigth	1.75 mm MAX
(FPT-8P)		

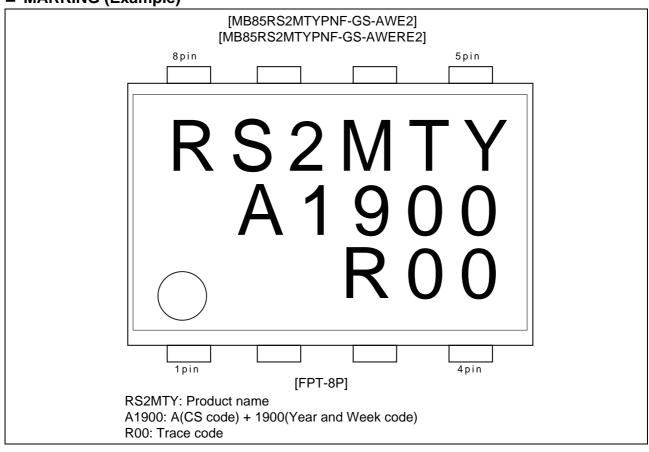


(Continued)





■ MARKING (Example)



[MB85RS2MTYPN-GS-AWEWE1]



[LCC-8P]

MB85RS2MTY: Product name

AE1: A(CS code) + E1(Environmental code)

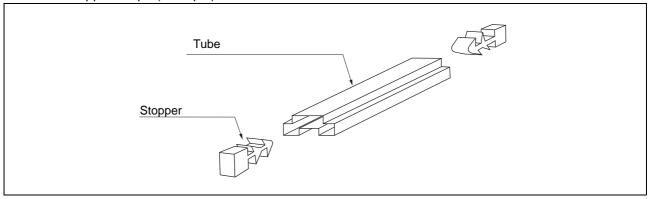
1900R00: 1900(Year and Week code) + R00(Trace code)

■ PACKING INFORMATION

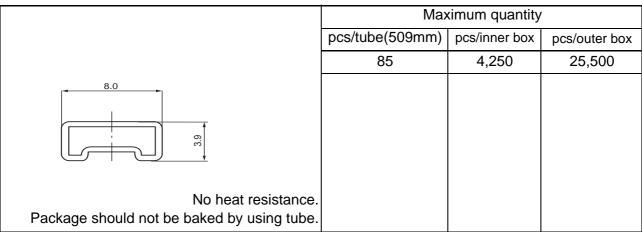
1. Tube

1.1 Tube Dimensions

• Tube/stopper shape (example)



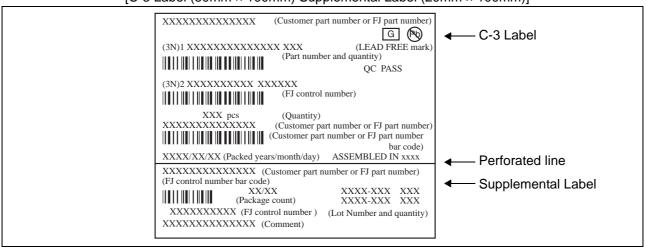
• Tube cross-sections and Maximum quantity



Dimensions in mm)

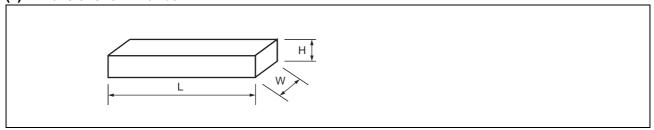
1.2 Product label indicators (example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]



1.3 Dimensions for Containers

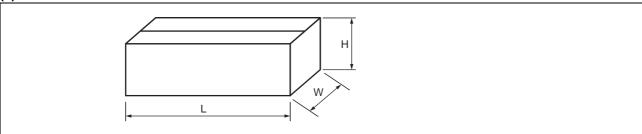
(1) Dimensions for inner box



L	W	Н
549	125	81

(Dimensions in mm)

(2) Dimensions for outer box

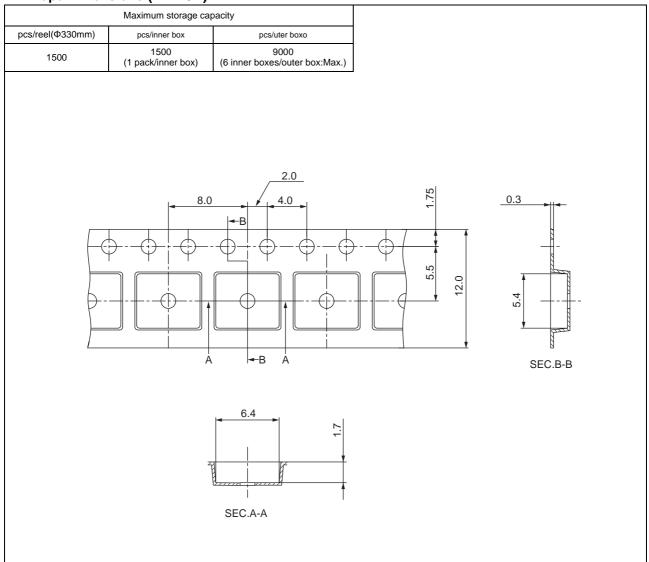


L	W	Н
567	272	269

(Dimensions in mm)

2. Emboss Tape

2.1 Tape Dimensions (FPT-8P)



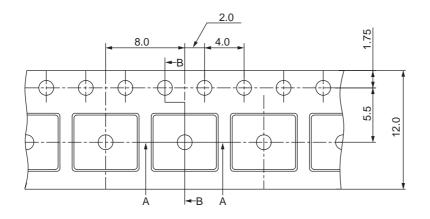
(Dimensions in mm)

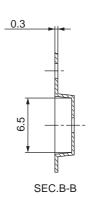
Heat proof temperature: No heat resistance.

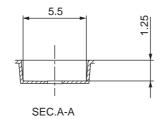
Package should not be baked by using tape and reel.

2.2 Tape Dimensions (LCC-8P)

Maximum storage capacity			
pcs/reel(Φ330mm) pcs/inner box pcs/uter boxo			
1500	1500 (1 pack/inner box)	9000 (6 inner boxes/outer box:Max)	







(Dimensions in mm)

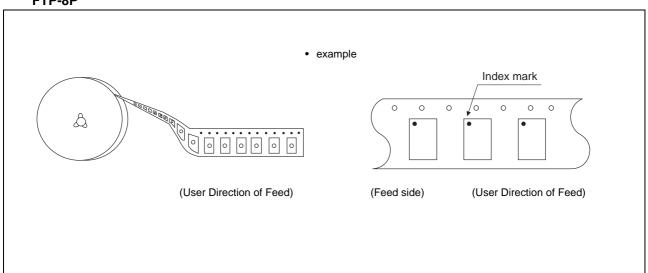
Heat proof temperature : No heat resistance.

Package should not be baked by using tape and

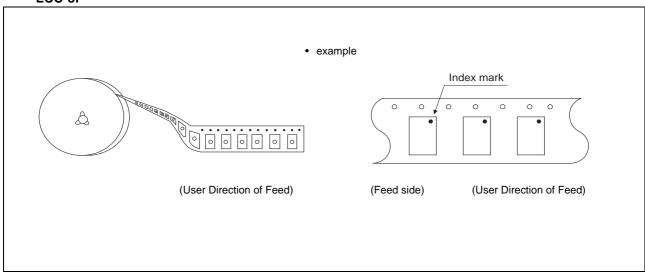
reel.

2.3 IC orientation

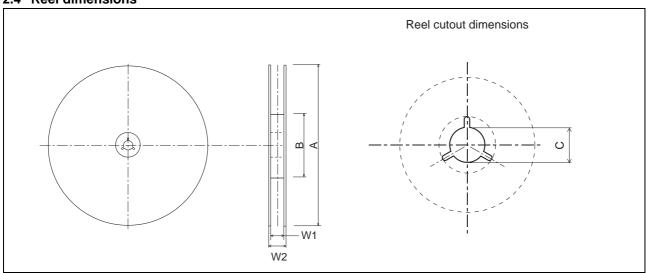
FTP-8P



LCC-8P



2.4 Reel dimensions

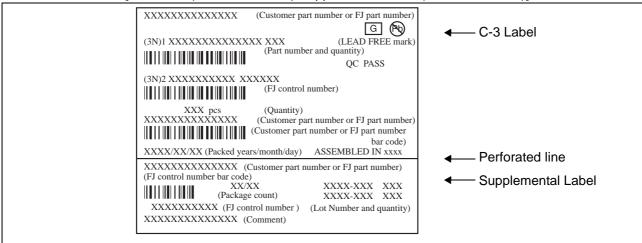


Dimensions in mm

Α	В	С	W1	W2
300	100	13	13.5	17.5

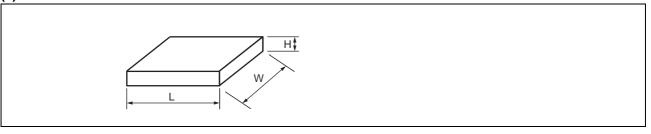
2.5 Product label indicators (example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label ($50mm \times 100mm$) Supplemental Label ($20mm \times 100mm$)]



2.6 Dimensions for Containers

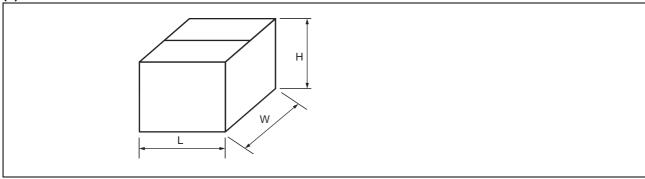
(1) Dimensions for inner box



Tape width	L	W	Н
12	350	335	35

(Dimensions in mm)

(2) Dimensions for outer box



L	W	Н
384	368	225

(Dimensions in mm)

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